

Second IEEE East-West Design and Test Workshop

Hahanov, Vladimir; **Ubar, Raimund-Johannes** IEEE journal of design & test of computers 2004 / p. 594

10th IEEE European Test Symposium

Ubar, Raimund-Johannes; Prinetto, Paolo; **Raik, Jaan** IEEE journal of design & test of computers 2005 / p. 480-481 : phot
<http://dx.doi.org/10.1109/MDT.2005.106>